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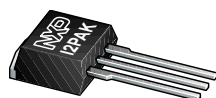
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# PSMN1R1-30EL

N-channel 30 V 1.3 mΩ logic level MOSFET in I2PAK

2 April 2014

Product data sheet

## 1. General description

Logic level N-channel MOSFET in I2PAK package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

## 2. Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

## 3. Applications

- DC-to-DC converters
- Load switching
- Motor control
- Server power supplies

## 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \geq 25\text{ °C}; T_j \leq 175\text{ °C}$		-	-	30	V
$I_D$	drain current	$T_{mb} = 25\text{ °C}; V_{GS} = 10\text{ V};$ <a href="#">Fig. 2</a>	[1]	-	-	120	A
$P_{tot}$	total power dissipation	$T_{mb} = 25\text{ °C};$ <a href="#">Fig. 1</a>		-	-	338	W
$T_j$	junction temperature			-55	-	175	°C
<b>Static characteristics</b>							
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = 10\text{ V}; I_D = 25\text{ A}; T_j = 25\text{ °C};$ <a href="#">Fig. 12</a>	[2]	-	1.1	1.3	mΩ
		$V_{GS} = 10\text{ V}; I_D = 25\text{ A}; T_j = 100\text{ °C};$ <a href="#">Fig. 13</a>		-	1.5	1.8	mΩ
<b>Dynamic characteristics</b>							
$Q_{GD}$	gate-drain charge	$V_{GS} = 4.5\text{ V}; I_D = 75\text{ A}; V_{DS} = 15\text{ V};$ <a href="#">Fig. 14; Fig. 15</a>		-	37	-	nC
$Q_{G(tot)}$	total gate charge			-	118	-	nC



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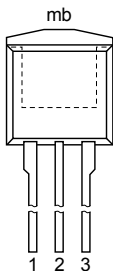
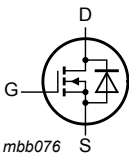
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Avalanche ruggedness</b>						
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$V_{GS} = 10\text{ V}$ ; $T_{j(\text{init})} = 25\text{ °C}$ ; $I_D = 120\text{ A}$ ; $V_{sup} \leq 30\text{ V}$ ; $R_{GS} = 50\text{ }\Omega$ ; unclamped	-	-	1.9	J

[1] Continuous current is limited by package.

[2] Measured 3 mm from package.

## 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	 <p>I2PAK (SOT226)</p>	
2	D	drain		
3	S	source		
mb	D	mounting base; connected to drain		

## 6. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN1R1-30EL	I2PAK	plastic single-ended package (I2PAK); TO-262	SOT226

## 7. Marking

Table 4. Marking codes

Type number	Marking code
PSMN1R1-30EL	PSMN1R1-30EL

## 8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \geq 25\text{ °C}$ ; $T_j \leq 175\text{ °C}$	-	30	V
$V_{DGR}$	drain-gate voltage	$T_j \geq 25\text{ °C}$ ; $T_j \leq 175\text{ °C}$ ; $R_{GS} = 20\text{ k}\Omega$	-	30	V

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Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>GS</sub>	gate-source voltage			-20	20	V
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; Fig. 1		-	338	W
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 100 °C; Fig. 2	[1]	-	120	A
		V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; Fig. 2	[1]	-	120	A
I <sub>DM</sub>	peak drain current	pulsed; t <sub>p</sub> ≤ 10 μs; T <sub>mb</sub> = 25 °C; Fig. 3		-	1609	A
T <sub>stg</sub>	storage temperature			-55	175	°C
T <sub>j</sub>	junction temperature			-55	175	°C
T <sub>slid(M)</sub>	peak soldering temperature			-	260	°C
<b>Source-drain diode</b>						
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	[1]	-	120	A
I <sub>SM</sub>	peak source current	pulsed; t <sub>p</sub> ≤ 10 μs; T <sub>mb</sub> = 25 °C		-	1609	A
<b>Avalanche ruggedness</b>						
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	V <sub>GS</sub> = 10 V; T <sub>j(init)</sub> = 25 °C; I <sub>D</sub> = 120 A; V <sub>sup</sub> ≤ 30 V; R <sub>GS</sub> = 50 Ω; unclamped		-	1.9	J

[1] Continuous current is limited by package.

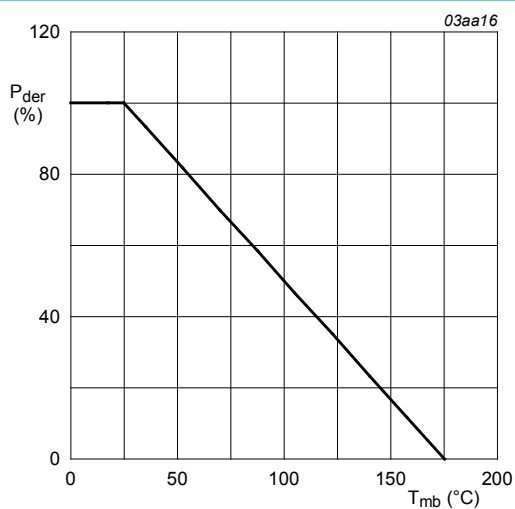


Fig. 1. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

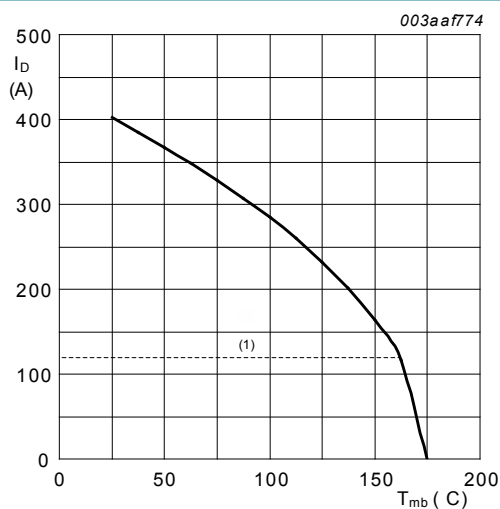


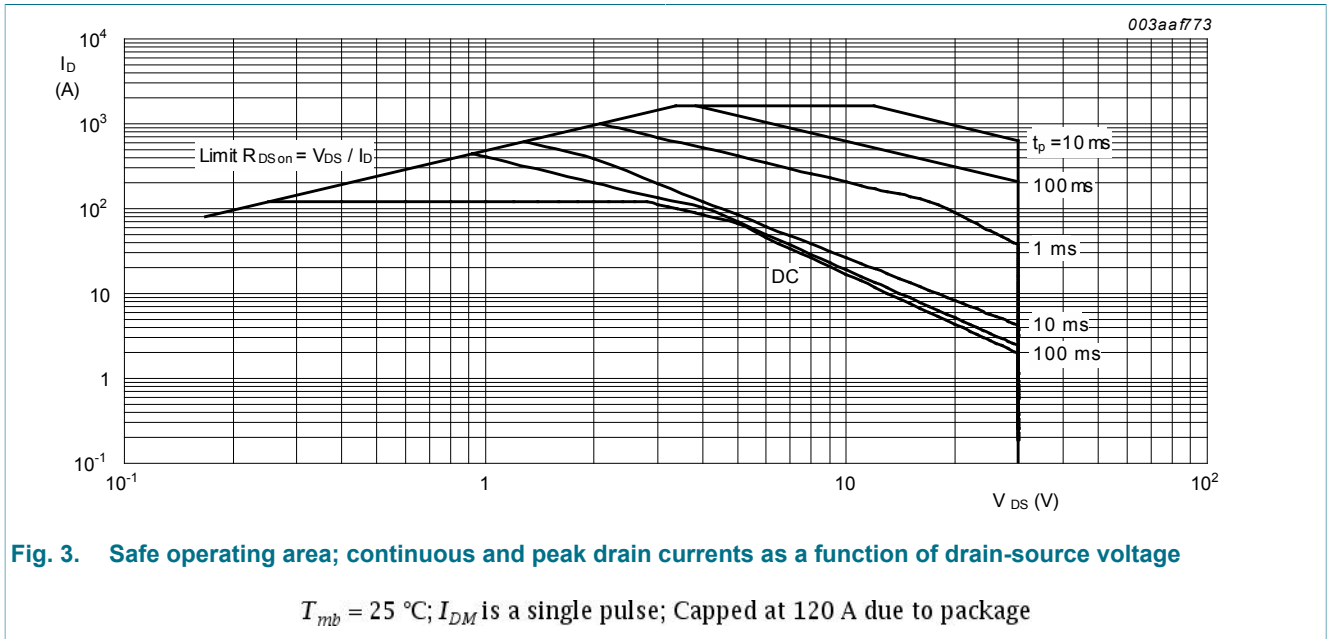
Fig. 2. Continuous drain current as a function of mounting base temperature.

V<sub>GS</sub> ≥ 10 V; (1) Capped at 120 A due to package

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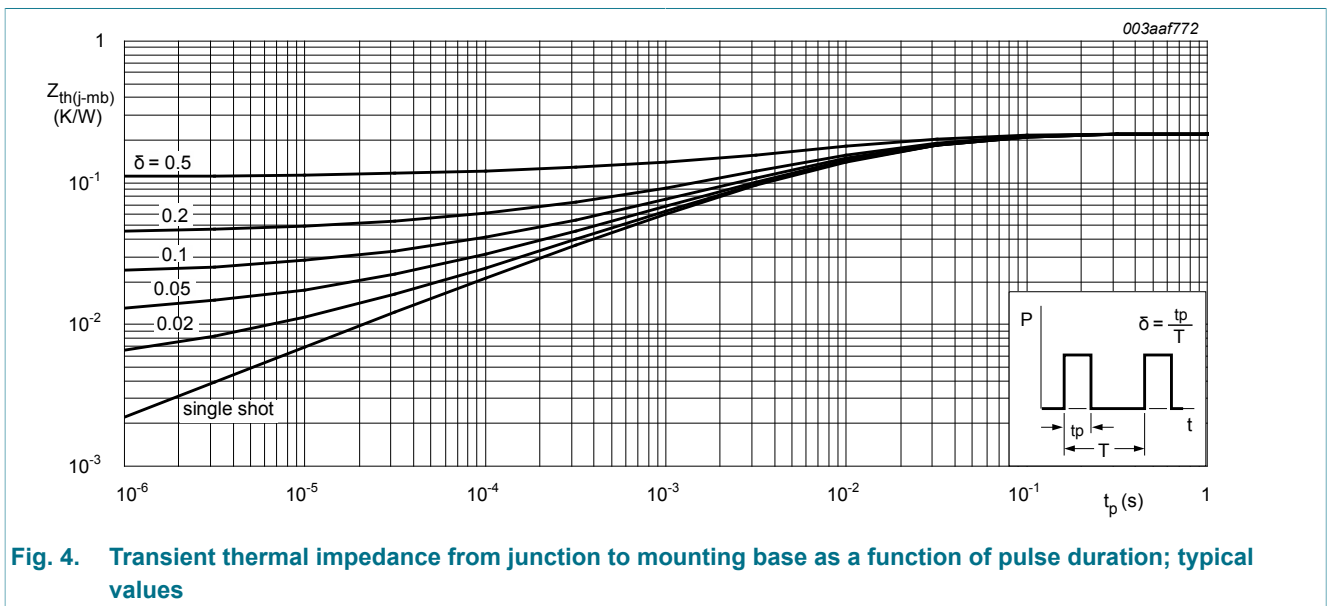
N-channel 30 V 1.3 mΩ logic level MOSFET in I2PAK



**9. Thermal characteristics**

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	Fig. 4	-	0.22	0.44	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	Vertical in free air	-	60	-	K/W



## 10. Characteristics

**Table 7. Characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static characteristics</b>						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$	30	-	-	V
		$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 \text{ }^\circ C$	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ }^\circ C;$ <a href="#">Fig. 10; Fig. 11</a>	1.3	1.7	2.15	V
		$I_D = 2 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ }^\circ C;$ <a href="#">Fig. 11</a>	0.5	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ }^\circ C;$ <a href="#">Fig. 11</a>	-	-	2.5	V
$I_{DSS}$	drain leakage current	$V_{DS} = 30 V; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$	-	0.02	10	$\mu A$
		$V_{DS} = 30 V; V_{GS} = 0 V; T_j = 175 \text{ }^\circ C$	-	250	500	$\mu A$
$I_{GSS}$	gate leakage current	$V_{GS} = 16 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	10	100	nA
		$V_{GS} = -16 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	10	100	nA
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = 10 V; I_D = 25 A; T_j = 25 \text{ }^\circ C;$ <a href="#">Fig. 12</a>	[1]	1.1	1.3	mΩ
		$V_{GS} = 4.5 V; I_D = 25 A; T_j = 25 \text{ }^\circ C;$ <a href="#">Fig. 12</a>	-	1.2	1.6	mΩ
		$V_{GS} = 10 V; I_D = 25 A; T_j = 175 \text{ }^\circ C;$ <a href="#">Fig. 13; Fig. 12</a>	-	2.1	2.5	mΩ
		$V_{GS} = 10 V; I_D = 25 A; T_j = 100 \text{ }^\circ C;$ <a href="#">Fig. 13</a>	-	1.5	1.8	mΩ
$R_G$	gate resistance	$f = 1 \text{ MHz}$	-	1.1	-	Ω
<b>Dynamic characteristics</b>						
$Q_{G(tot)}$	total gate charge	$I_D = 75 A; V_{DS} = 15 V; V_{GS} = 10 V;$ <a href="#">Fig. 14; Fig. 15</a>	-	243	-	nC
		$I_D = 0 A; V_{DS} = 0 V; V_{GS} = 10 V;$ <a href="#">Fig. 14; Fig. 15</a>	-	222	-	nC
		$I_D = 75 A; V_{DS} = 15 V; V_{GS} = 4.5 V;$ <a href="#">Fig. 14; Fig. 15</a>	-	118	-	nC
$Q_{GS}$	gate-source charge		-	39	-	nC
$Q_{GS(th)}$	pre-threshold gate-source charge		-	22	-	nC
$Q_{GS(th-pl)}$	post-threshold gate-source charge		-	17	-	nC
$Q_{GD}$	gate-drain charge		-	37	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$V_{DS} = 15 V;$ <a href="#">Fig. 14; Fig. 15</a>	-	2.8	-	V

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Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$C_{iss}$	input capacitance	$V_{DS} = 15\text{ V}; V_{GS} = 0\text{ V}; f = 1\text{ MHz}; T_j = 25\text{ }^\circ\text{C}; \text{Fig. 16}$	-	14850	-	pF
$C_{oss}$	output capacitance		-	2799	-	pF
$C_{rss}$	reverse transfer capacitance		-	1215	-	pF
$t_{d(on)}$	turn-on delay time	$V_{DS} = 15\text{ V}; R_L = 0.2\text{ } \Omega; V_{GS} = 4.5\text{ V}; R_{G(ext)} = 5\text{ } \Omega; I_D = 75\text{ A}; T_j = 25\text{ }^\circ\text{C}$	-	95	-	ns
$t_r$	rise time		-	213	-	ns
$t_{d(off)}$	turn-off delay time		-	199	-	ns
$t_f$	fall time		-	115	-	ns
<b>Source-drain diode</b>						
$V_{SD}$	source-drain voltage	$I_S = 25\text{ A}; V_{GS} = 0\text{ V}; T_j = 25\text{ }^\circ\text{C}; \text{Fig. 17}$	-	0.8	1.2	V
$t_{rr}$	reverse recovery time	$I_S = 25\text{ A}; di_S/dt = -100\text{ A}/\mu\text{s}; V_{GS} = 0\text{ V}; V_{DS} = 15\text{ V}$	-	67	-	ns
$Q_r$	recovered charge		-	123	-	nC

[1] Measured 3 mm from package.

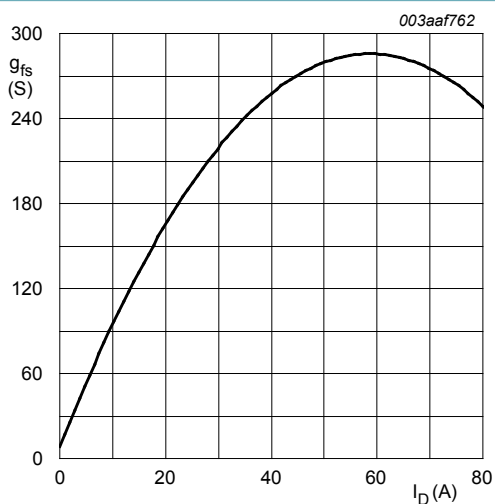


Fig. 5. Forward transconductance as a function of drain current; typical values

$$T_j = 25\text{ }^\circ\text{C}; V_{DS} = 15\text{ V}$$

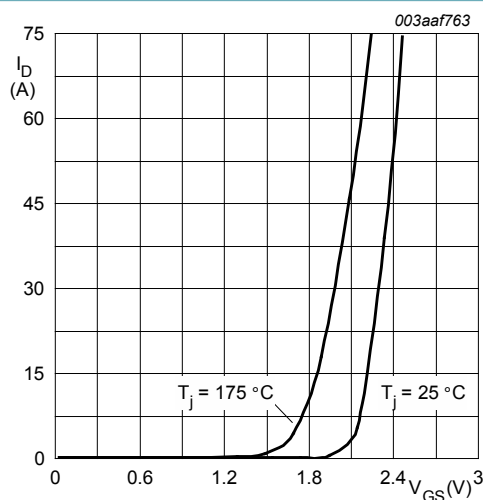


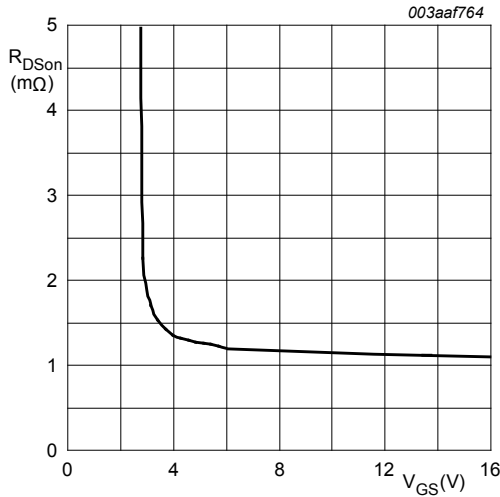
Fig. 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

$$V_{DS} > I_D \times R_{DS(on)}$$

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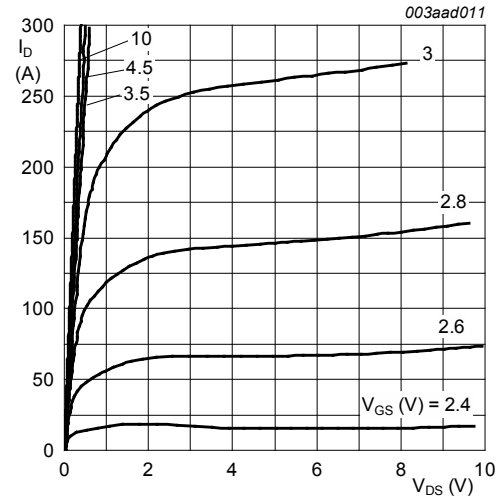
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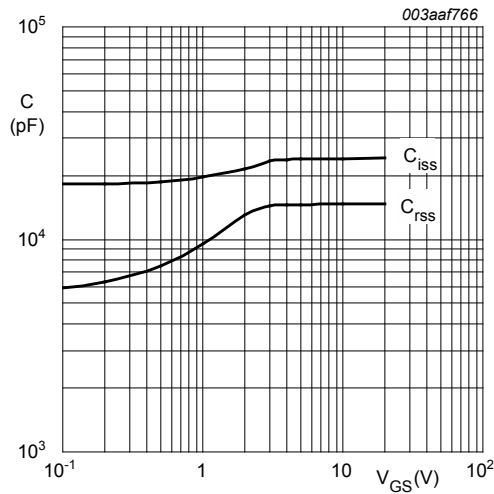
**Fig. 7. Drain-source on-state resistance as a function of gate-source voltage; typical values**

$T_J = 25^\circ\text{C}; I_D = 25\text{A}$



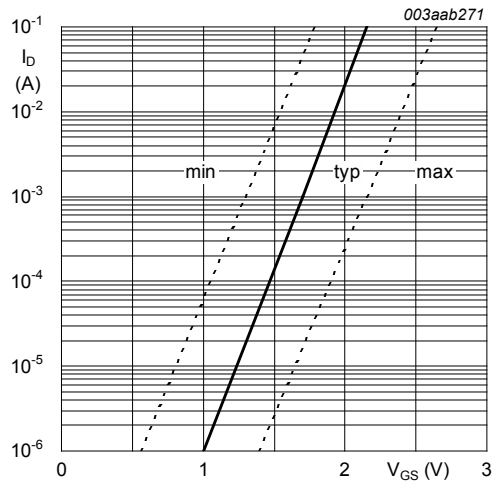
**Fig. 8. Output characteristics: drain current as a function of drain-source voltage; typical values**

$T_J = 25^\circ\text{C}$



**Fig. 9. Input and reverse transfer capacitances as a function of gate-source voltage; typical values**

$V_{DS} = 0\text{V}; f = 1\text{MHz}$



**Fig. 10. Sub-threshold drain current as a function of gate-source voltage**

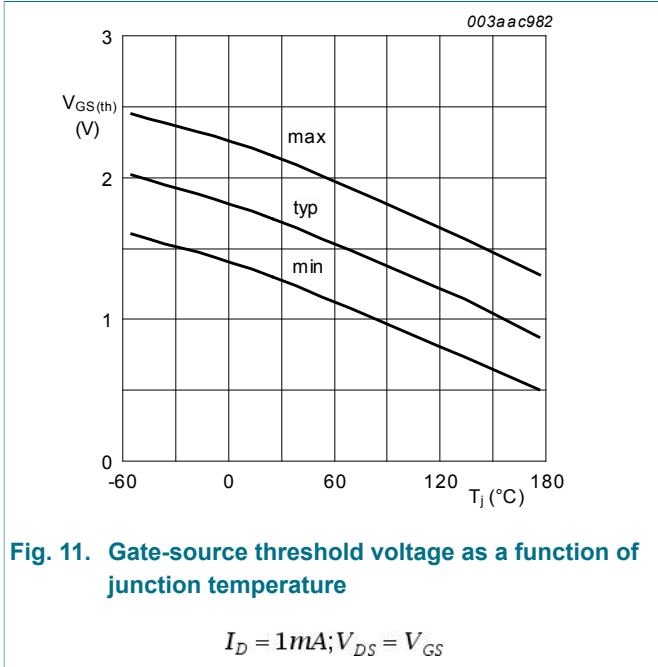
$T_J = 25^\circ\text{C}; V_{DS} = 5\text{V}$



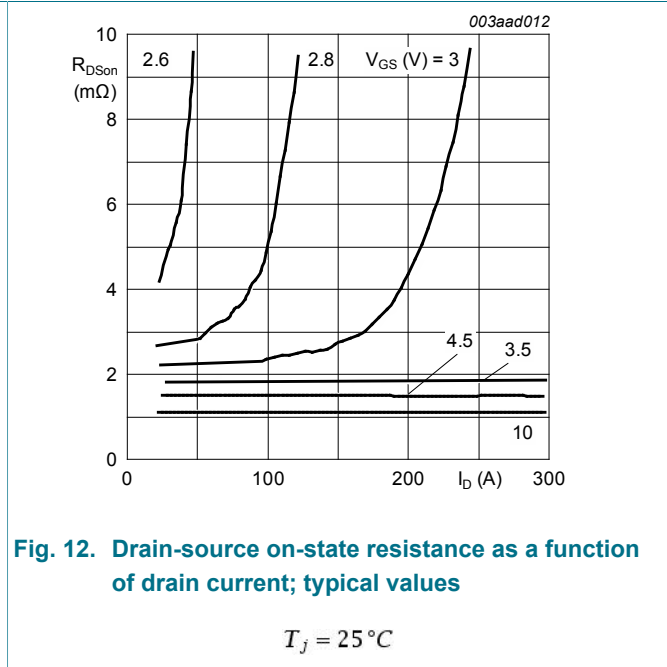
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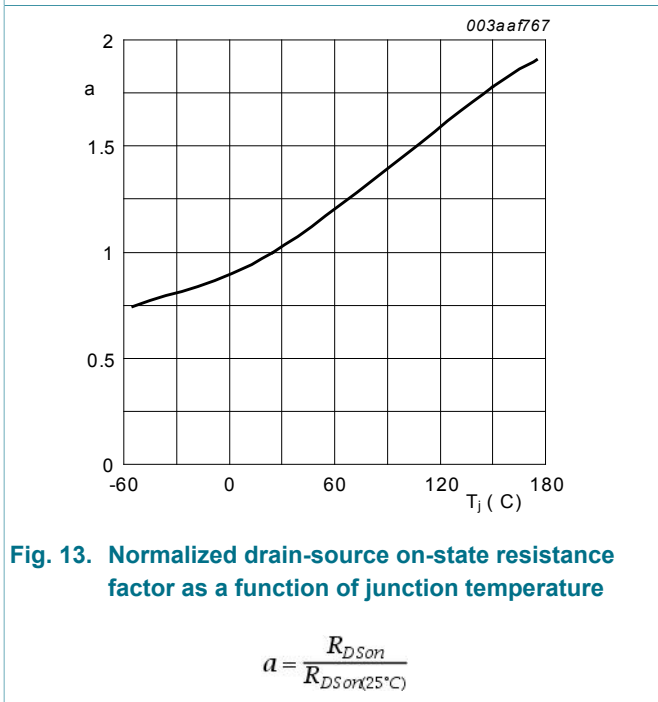
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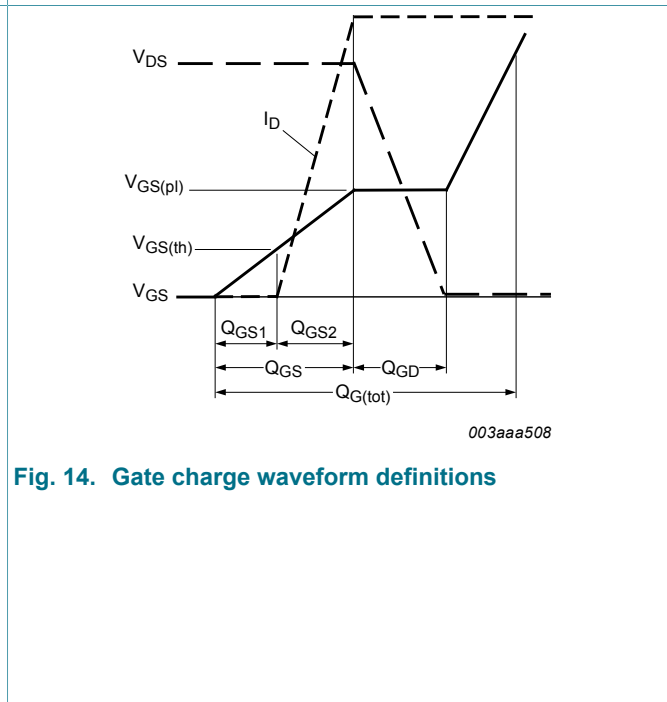
**Fig. 11. Gate-source threshold voltage as a function of junction temperature**



**Fig. 12. Drain-source on-state resistance as a function of drain current; typical values**



**Fig. 13. Normalized drain-source on-state resistance factor as a function of junction temperature**

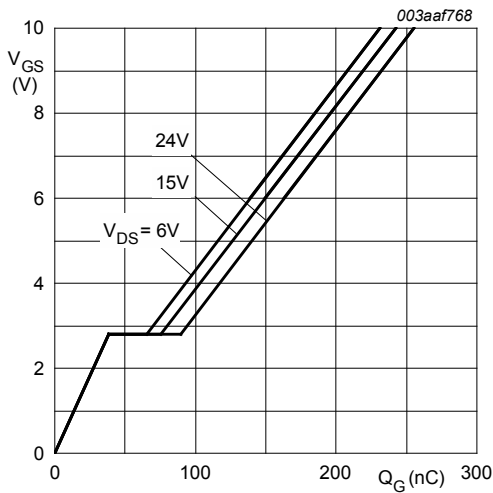


**Fig. 14. Gate charge waveform definitions**

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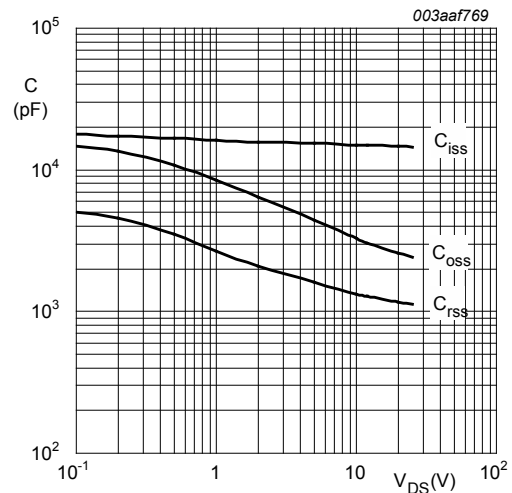
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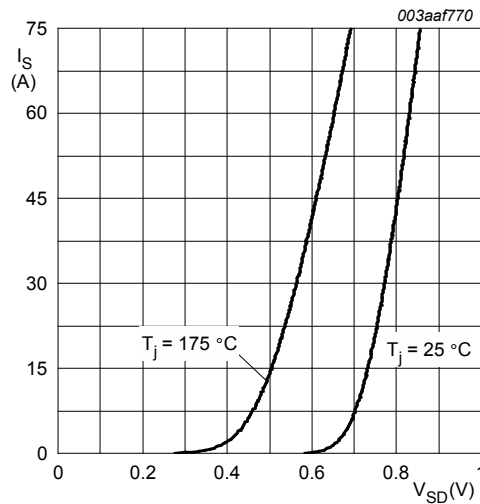
**Fig. 15. Gate-source voltage as a function of gate charge; typical values**

$T_j = 25\text{ }^\circ\text{C}; I_D = 75\text{ A}$



**Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values**

$V_{GS} = 0\text{ V}; f = 1\text{ MHz}$



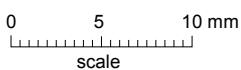
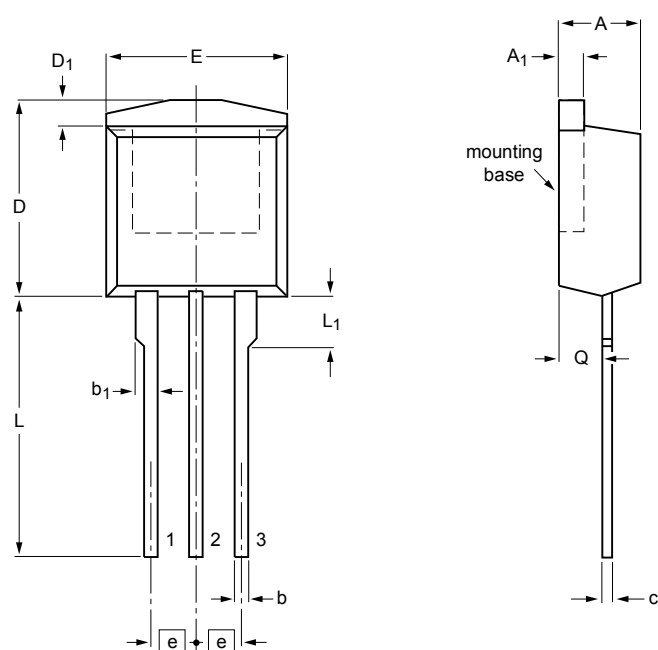
**Fig. 17. Source current as a function of source-drain voltage; typical values**

$V_{GS} = 0\text{ V}$

## 11. Package outline

Plastic single-ended package (I2PAK); low-profile 3-lead TO-262

SOT226



DIMENSIONS (mm are the original dimensions)

UNIT	A	A <sub>1</sub>	b	b <sub>1</sub>	c	D <sub>max</sub>	D <sub>1</sub>	E	e	L	L <sub>1</sub>	Q
mm	4.5 4.1	1.40 1.27	0.85 0.60	1.3 1.0	0.7 0.4	11	1.6 1.2	10.3 9.7	2.54	15.0 13.5	3.30 2.79	2.6 2.2

OUTLINE VERSION	REFERENCES			EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA		
SOT226		TO-262			-06-02-14 09-08-25

Fig. 18. Package outline I2PAK (SOT226)

## 12. Legal information

### 12.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.  
 [2] The term 'short data sheet' is explained in section "Definitions".  
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